

Preparation of White Light Emitting $\text{YVO}_4: \text{Ln}^{3+}$ and Silica-coated $\text{YVO}_4: \text{Ln}^{3+}$

($\text{Ln}^{3+} = \text{Eu}^{3+}, \text{Dy}^{3+}, \text{Tm}^{3+}$) Nanoparticles by CTAB/n-butanol/hexane/water

Microemulsion Route: Energy Transfer and Site Symmetry Studies

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Table S1.	V-O charge transfer in the excitation spectra of $\text{YVO}_4:\text{Ln}^{3+}$ and $\text{YVO}_4:\text{Ln}^{3+}@\text{SiO}_2$ ($\text{Ln}^{3+} = \text{Eu}^{3+}, \text{Tm}^{3+}$ and Dy^{3+}) at different annealing temperatures.
Table S2.	Integrated Area and Full width half maximum (FWHM) of the electric and magnetic dipole transition of the emission spectra of $\text{Ln}^{3+}:\text{YVO}_4$ and $\text{Ln}^{3+}:\text{YVO}_4@\text{SiO}_2$ ($\text{Ln}^{3+} = \text{Eu}^{3+}, \text{Tm}^{3+}$ and Dy^{3+}) at different annealing temperatures.
Table S3.	Lifetime values (mono-exponential fitting) for Ln^{3+} ($\text{Ln}^{3+} = \text{Eu}^{3+}, \text{Tm}^{3+}$ and Dy^{3+}) in $\text{YVO}_4:\text{Ln}^{3+}$ and $\text{YVO}_4:\text{Ln}^{3+}@\text{SiO}_2$ at different annealing temperatures.
Fig. S1	XRD patterns of $\text{YVO}_4:\text{Ln}^{3+}$ ($\text{Ln}^{3+} = \text{Eu}^{3+}, \text{Dy}^{3+}, \text{Tm}^{3+}$) at different annealing temperatures (500 and 900 °C).
Fig. S2	XRD patterns of $\text{YVO}_4:\text{Ln}^{3+}@\text{SiO}_2$ ($\text{Ln}^{3+} = \text{Eu}^{3+}, \text{Dy}^{3+}, \text{Tm}^{3+}$) at different annealing temperatures (500, 700 and 900 °C).
Fig. S3	TGA curve of as-prepared YVO_4 collected from CTAB/n-butanol/hexane/water microemulsion.
Fig. S4	TEM images of $\text{YVO}_4:\text{Tm}^{3+}@\text{SiO}_2$ annealed at (a) 500 and (b) 900°C. Inset of (b) shows the SAED (Upper) and HRTEM (Lower).
Fig. S5	Luminescence decay of $\text{YVO}_4:\text{Ln}^{3+}$ ($\text{Ln}^{3+} = \text{Eu}^{3+}, \text{Dy}^{3+}$ and Tm^{3+}) at different annealing temperatures (500 and 900 °C).
Fig. S6	Luminescence decay of $\text{YVO}_4:\text{Ln}^{3+}@\text{SiO}_2$ ($\text{Ln}^{3+} = \text{Eu}^{3+}, \text{Dy}^{3+}$ or Tm^{3+}) at different annealing temperatures (500 and 900 °C).
Fig. S7	Luminescence decay of $\text{YVO}_4:\text{Ln}^{3+}@\text{SiO}_2$ ($\text{Ln}^{3+} = \text{Eu}^{3+}, \text{Dy}^{3+}$ and Tm^{3+}) at different annealing temperatures (500 and 900 °C).

Table S1. V-O charge transfer in the excitation spectra of $\text{YVO}_4:\text{Ln}^{3+}$ and $\text{YVO}_4:\text{Ln}^{3+}@\text{SiO}_2$ ($\text{Ln}^{3+} = \text{Eu}^{3+}$, Tm^{3+} and Dy^{3+}) at different annealing temperatures.

Sl. No.	Sample	V-O Charge transfer (nm)
1	Eu: YVO_4 – 500 °C	300
2	Eu: YVO_4 – 900 °C	318
3	Eu: $\text{YVO}_4 @\text{SiO}_2$ – 500 °C	290
4	Eu: $\text{YVO}_4 @\text{SiO}_2$ – 900 °C	307
5	Dy: YVO_4 – 500 °C	300
6	Dy: YVO_4 – 900 °C	320
7	Dy: $\text{YVO}_4 @\text{SiO}_2$ – 500 °C	300
8	Dy: $\text{YVO}_4 @\text{SiO}_2$ – 900 °C	306
9	Tm: YVO_4 – 500 °C	303
10	Tm: YVO_4 – 900 °C	320
11	Tm: $\text{YVO}_4 @\text{SiO}_2$ – 500 °C	295
12	Tm: $\text{YVO}_4 @\text{SiO}_2$ – 900 °C	310

Table S2. Integrated area and full width half maximum (FWHM) of the electric and magnetic dipole transition of the emission spectra of $\text{Ln}^{3+}:\text{YVO}_4$ and $\text{Ln}^{3+}:\text{YVO}_4@\text{SiO}_2$ ($\text{Ln}^{3+} = \text{Eu}^{3+}$, Tm^{3+} and Dy^{3+}) at different annealing temperatures.

Sl. No.	Sample	Electric dipole transition		Magnetic dipole transition	
		Integrated area	FWHM (nm)	Integrated area	FWHM (nm)
1	$\text{Eu}:\text{YVO}_4 - 500\text{ }^\circ\text{C}$	2.3×10^4	6.7	2.1×10^3	5.4
2	$\text{Eu}:\text{YVO}_4 - 900\text{ }^\circ\text{C}$	4.4×10^5	6.3	5.3×10^4	3.7
3	$\text{Eu}:\text{YVO}_4 @\text{SiO}_2 - 500\text{ }^\circ\text{C}$	3.5×10^5	6.4	3.5×10^4	4.1
4	$\text{Eu}:\text{YVO}_4 @\text{SiO}_2 - 900\text{ }^\circ\text{C}$	1.6×10^7	6.1	1.84×10^6	4.1
5	$\text{Dy}:\text{YVO}_4 - 500\text{ }^\circ\text{C}$	1.6×10^5	6.5	4.3×10^5	9.2
6	$\text{Dy}:\text{YVO}_4 - 900\text{ }^\circ\text{C}$	3.9×10^5	6.0	1.5×10^5	9.1
7	$\text{Dy}:\text{YVO}_4 @\text{SiO}_2 - 500\text{ }^\circ\text{C}$	2.2×10^3	6.6	8.9×10^2	8.8
8	$\text{Dy}:\text{YVO}_4 @\text{SiO}_2 - 900\text{ }^\circ\text{C}$	1.3×10^6	7.2	4.9×10^5	8.8
9	$\text{Tm}:\text{YVO}_4 - 500\text{ }^\circ\text{C}$	1.1×10^4	7.8	-	-
10	$\text{Tm}:\text{YVO}_4 - 900\text{ }^\circ\text{C}$	2.5×10^5	7.7	-	-
11	$\text{Tm}:\text{YVO}_4 @\text{SiO}_2 - 500\text{ }^\circ\text{C}$	1.9×10^4	9.7	-	-
12	$\text{Tm}:\text{YVO}_4 @\text{SiO}_2 - 900\text{ }^\circ\text{C}$	6.3×10^5	7.9	-	-

Table S3. Lifetime values obtained after the mono-exponential fitting to the data of $\text{YVO}_4:\text{Ln}^{3+}$ and $\text{YVO}_4:\text{Ln}^{3+}@\text{SiO}_2$ ($\text{Ln}^{3+} = \text{Eu}^{3+}$, Tm^{3+} and Dy^{3+}) at different annealing temperatures.

Sl. No.	Sample	Lifetime, τ (μs)	R^2 (Goodness of parameter)
1.	Tm: YVO_4 – 500 °C	13.3	0.997
2.	Tm: YVO_4 – 900 °C	16.3	0.991
3.	Eu: YVO_4 – 500 °C	149.9	0.974
4.	Eu: YVO_4 – 900 °C	475.4	0.998
5.	Dy: YVO_4 – 500 °C	84.6	0.987
6.	Dy: YVO_4 – 900 °C	109.1	0.999
7.	Tm:Eu:Dy: YVO_4 – 500 °C (Tm)	2.5	0.974
8.	Tm:Eu:Dy: YVO_4 – 500 °C (Eu)	16.8	0.996
9.	Tm:Eu:Dy: YVO_4 – 500 °C (Dy)	4.9	0.979
10.	Tm:Eu:Dy: YVO_4 – 900 °C (Tm)	4.1	0.977
11.	Tm:Eu:Dy: YVO_4 – 900 °C (Eu)	24.4	0.991
12.	Tm:Eu:Dy: YVO_4 – 900 °C (Dy)	11.7	0.961
13.	Tm: $\text{YVO}_4@\text{SiO}_2$ – 500 °C	5.4	0.969
14.	Tm: $\text{YVO}_4 @\text{SiO}_2$ – 900 °C	21.1	0.998
15.	Eu: $\text{YVO}_4 @\text{SiO}_2$ – 500 °C	264.9	0.973
16.	Eu: $\text{YVO}_4 @\text{SiO}_2$ – 900 °C	629.5	0.998
17.	Dy: $\text{YVO}_4 @\text{SiO}_2$ – 500 °C	36.1	0.924
18.	Dy: $\text{YVO}_4 @\text{SiO}_2$ – 900 °C	210.9	0.996
19.	Tm:Eu:Dy: $\text{YVO}_4 @\text{SiO}_2$ – 500 °C (Tm)	1.9	0.969
20.	Tm:Eu:Dy: $\text{YVO}_4 @\text{SiO}_2$ – 500 °C (Eu)	12.4	0.993
21.	Tm:Eu:Dy: $\text{YVO}_4 @\text{SiO}_2$ – 500 °C (Dy)	4.5	0.979
22.	Tm:Eu:Dy: $\text{YVO}_4 @\text{SiO}_2$ – 900 °C (Tm)	4.5	0.962
23.	Tm:Eu:Dy: $\text{YVO}_4 @\text{SiO}_2$ – 900 °C (Eu)	25.6	0.991
24.	Tm:Eu:Dy: $\text{YVO}_4 @\text{SiO}_2$ – 900 °C (Dy)	11.9	0.959

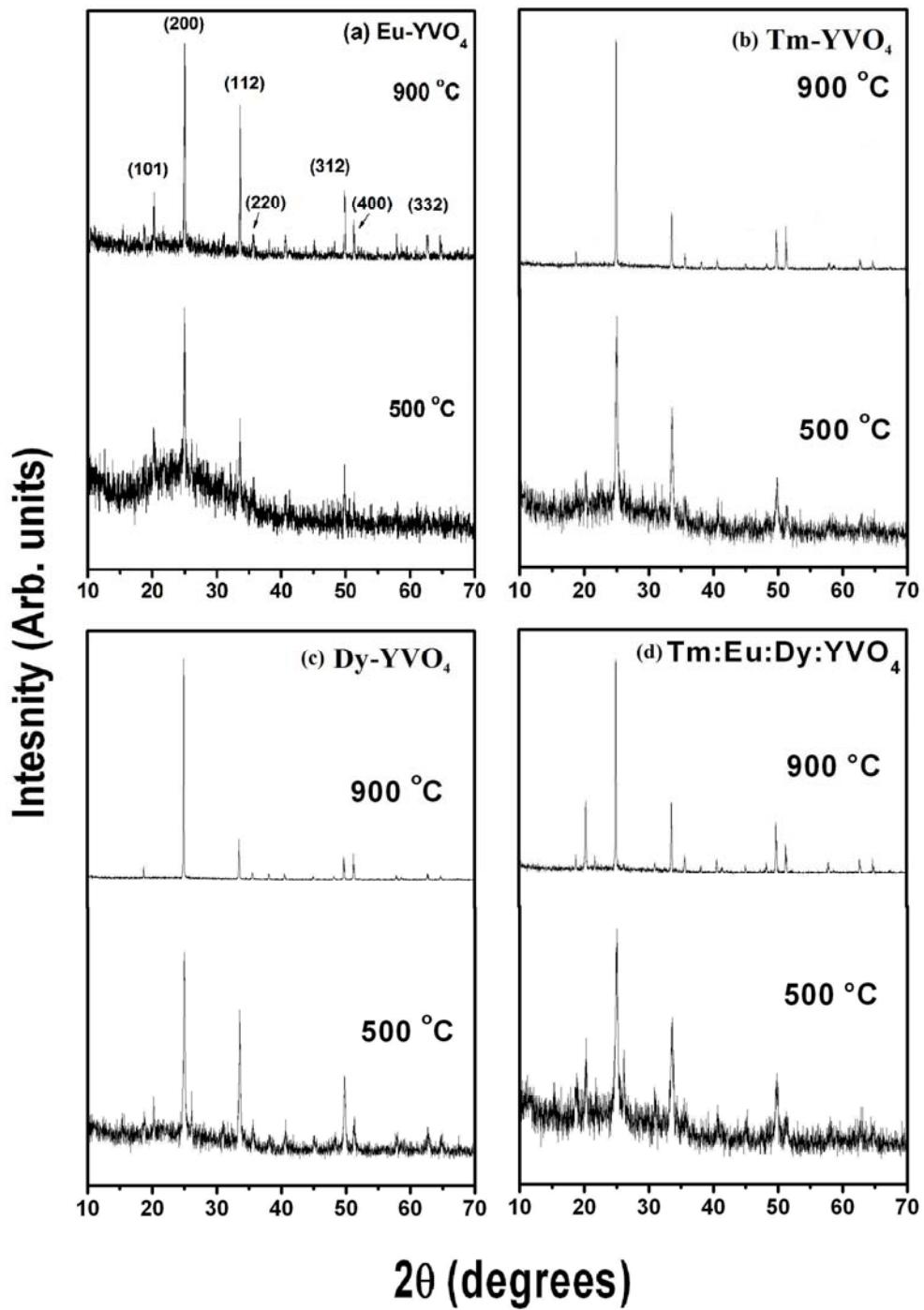


Fig. S1 XRD patterns of $\text{YVO}_4:\text{Ln}^{3+}$ ($\text{Ln}^{3+} = \text{Eu}^{3+}, \text{Dy}^{3+}, \text{Tm}^{3+}$) at different annealing temperatures (500 and 900 °C).

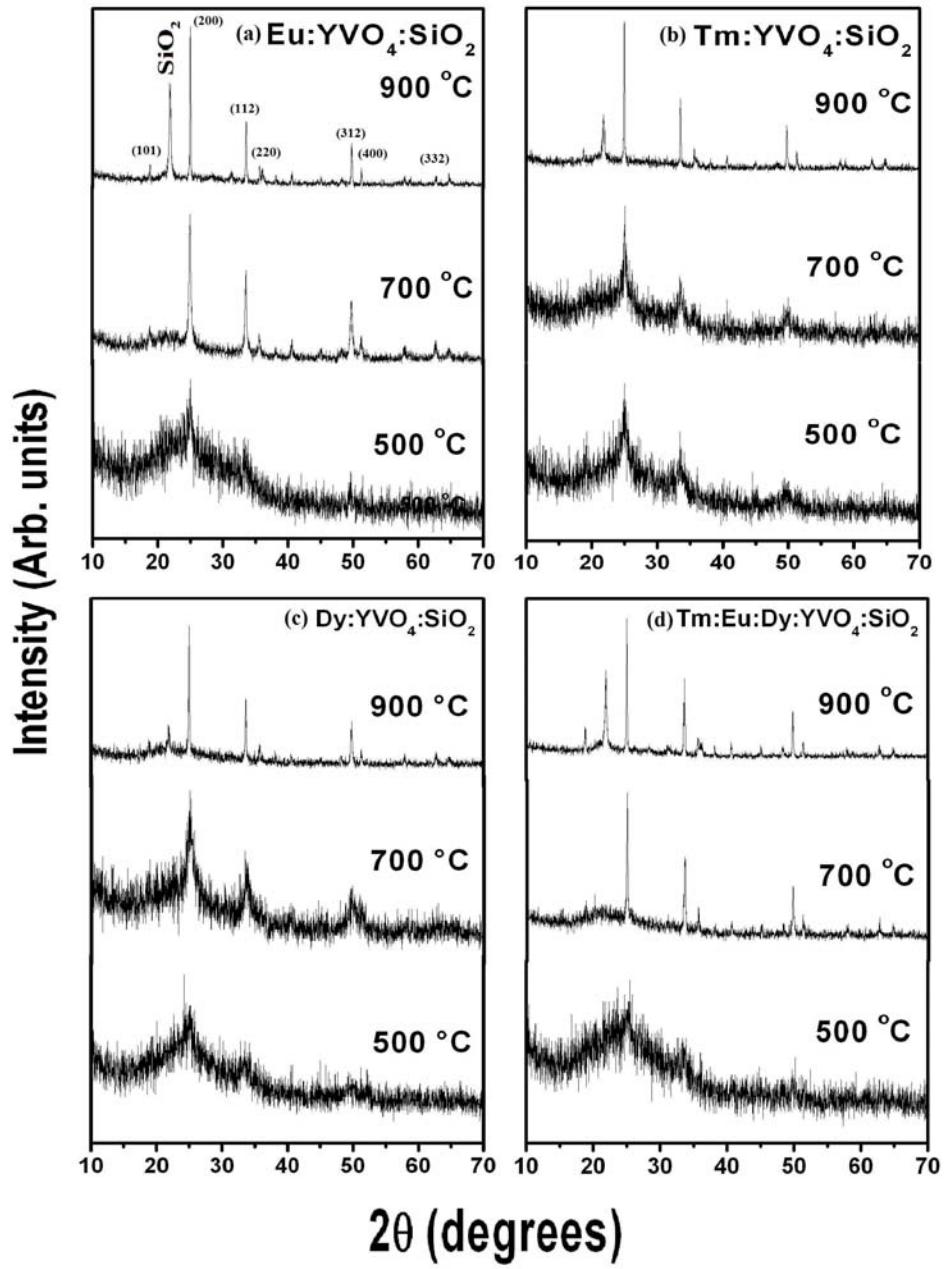


Fig. S2 XRD patterns of YVO₄:Ln³⁺@SiO₂ (Ln³⁺ = Eu³⁺, Dy³⁺, Tm³⁺) at different annealing temperatures (500, 700 and 900 °C).

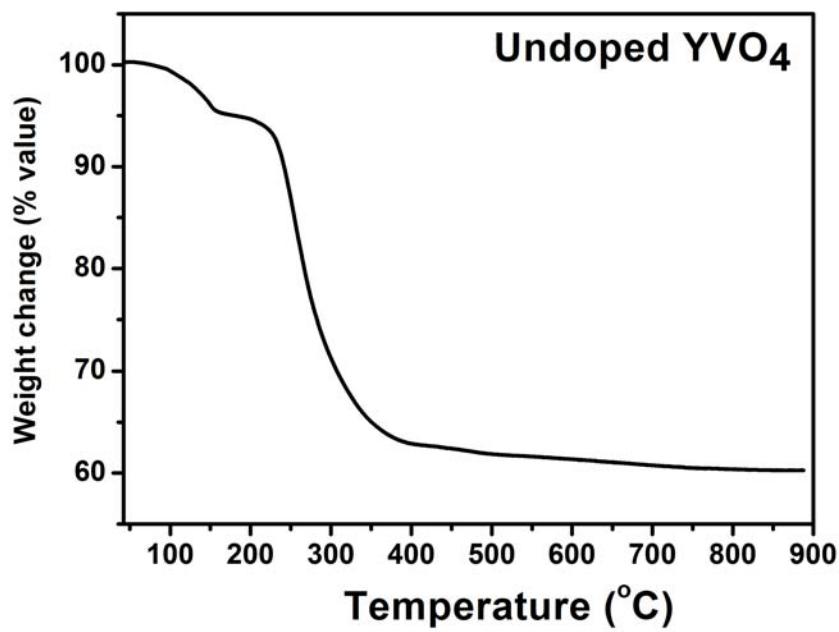


Fig. S3 TGA curve of as-prepared YVO₄ collected from CTAB/n-butanol/hexane/water microemulsion.

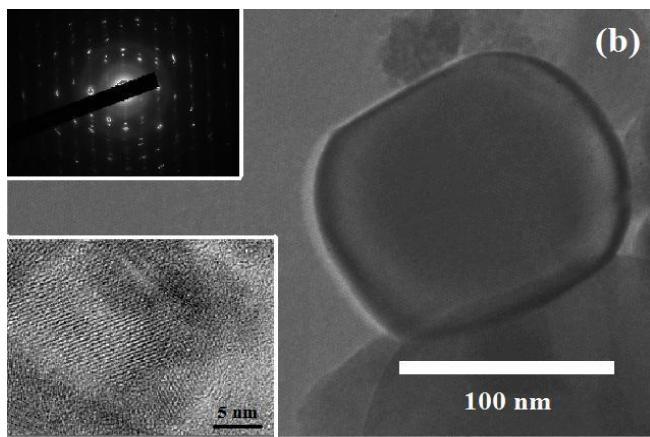
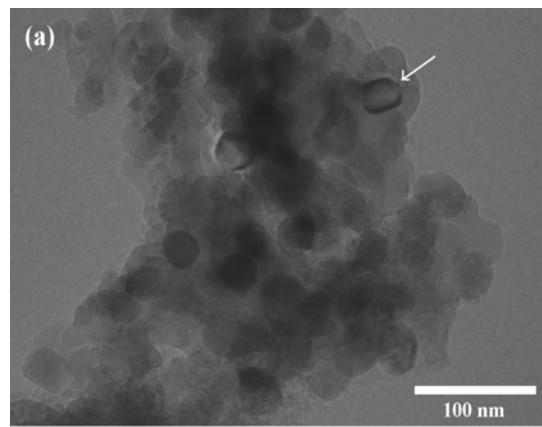


Fig. S4 TEM images of $\text{YVO}_4:\text{Tm}^{3+}@\text{SiO}_2$ annealed at (a) 500 and (b) 900°C. Inset of (b) shows the SAED (Upper) and HRTEM (Lower).

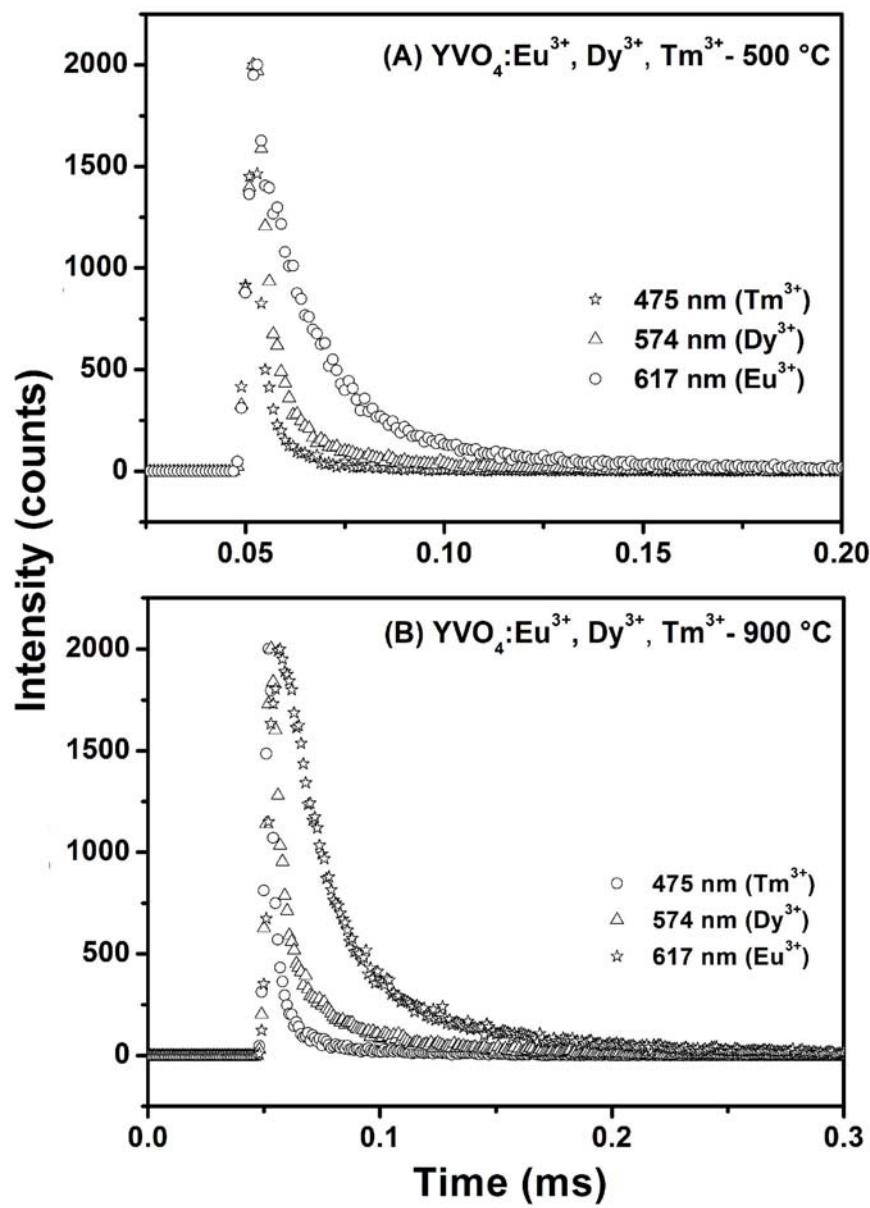


Fig. S5 Luminescence decay of $\text{YVO}_4:\text{Ln}^{3+}$ ($\text{Ln}^{3+} = \text{Eu}^{3+}, \text{Dy}^{3+}$ and Tm^{3+}) at different annealing temperatures (500 and 900 °C).

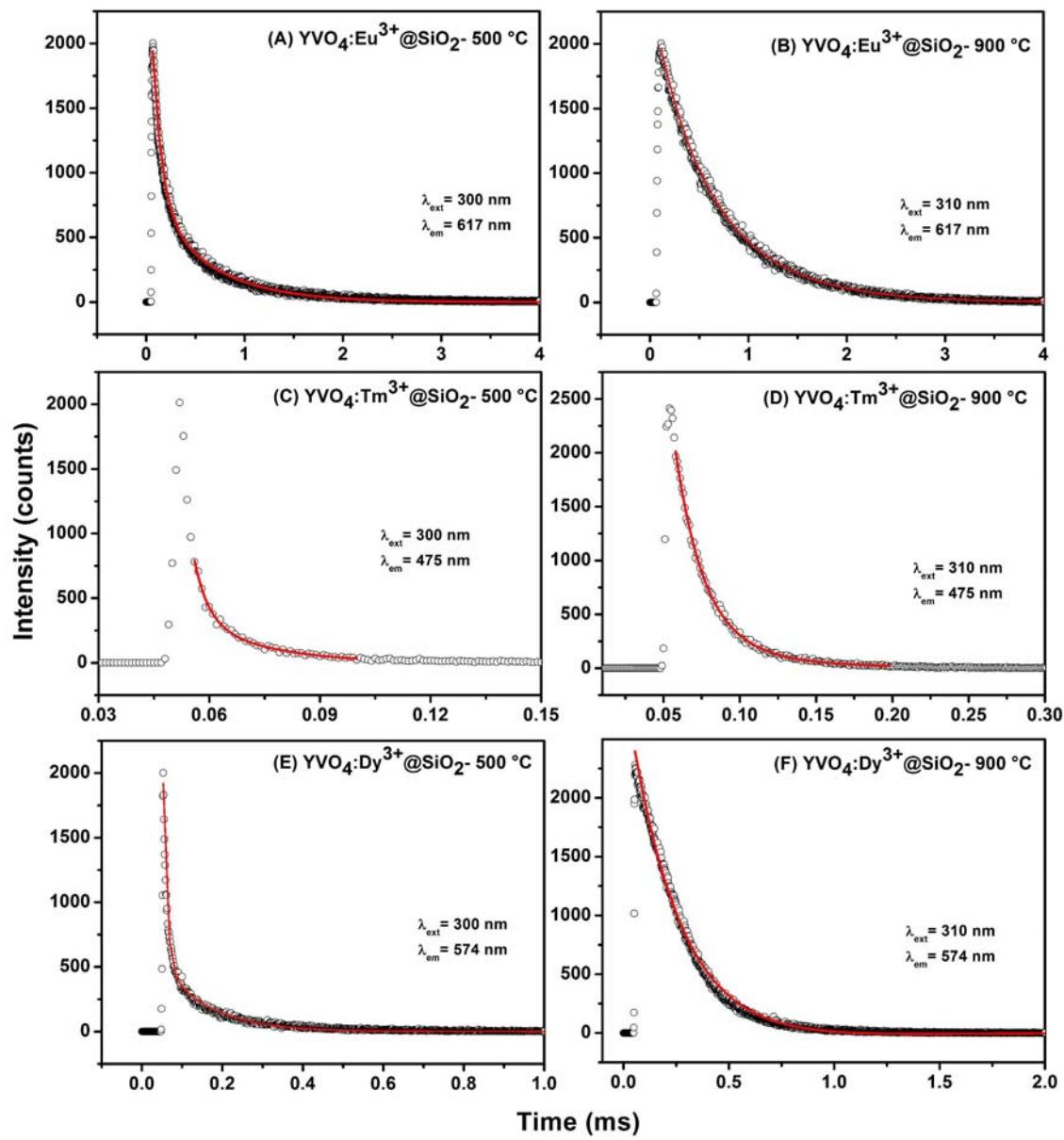


Fig. S6 Luminescence decay of $\text{YVO}_4:\text{Ln}^{3+}\text{@SiO}_2$ ($\text{Ln}^{3+} = \text{Eu}^{3+}, \text{Dy}^{3+}$ or Tm^{3+}) at different annealing temperatures (500 and 900 °C).

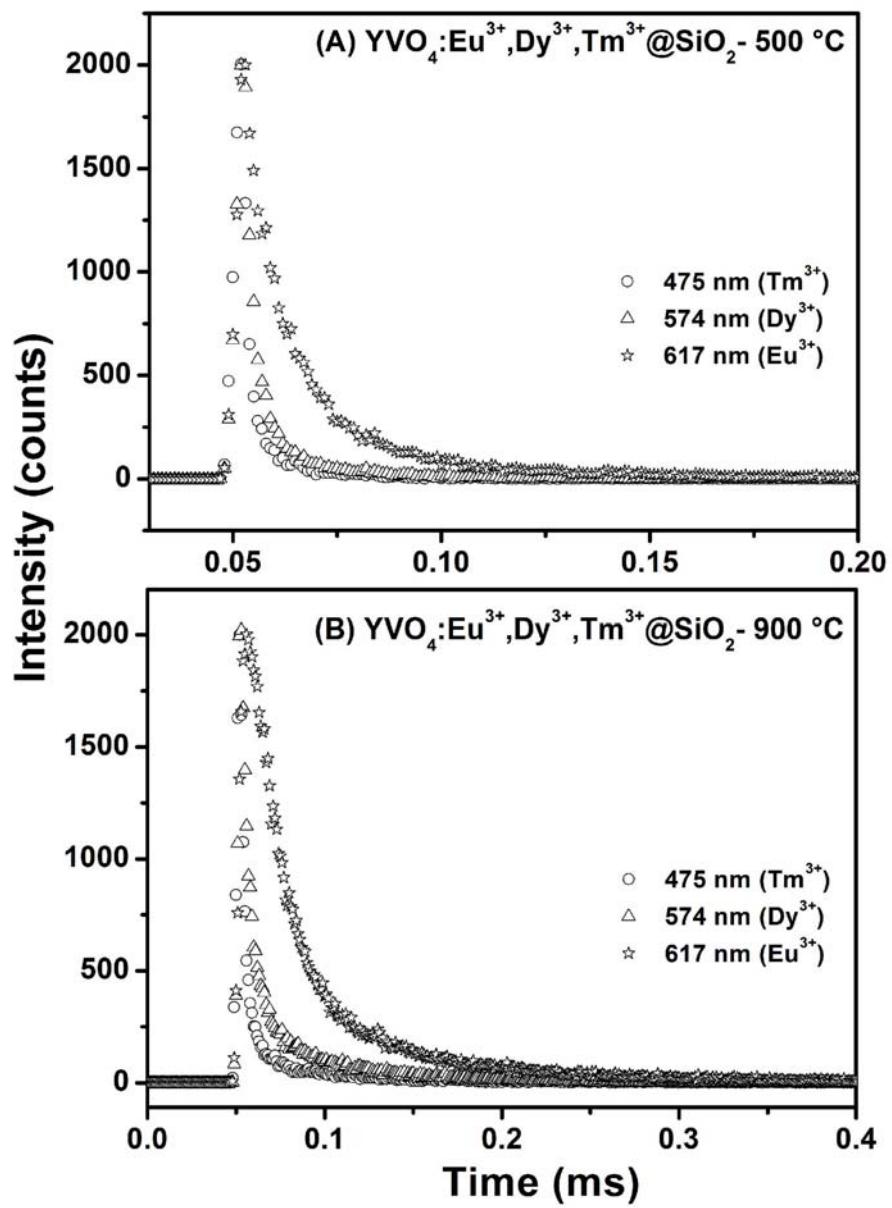


Fig. S7 Luminescence decay of $\text{YVO}_4:\text{Ln}^{3+}@\text{SiO}_2$ ($\text{Ln}^{3+} = \text{Eu}^{3+}, \text{Dy}^{3+}$ and Tm^{3+}) at different annealing temperatures (500 and $900\text{ }^{\circ}\text{C}$).